

# **Device Modeling Report**

COMPONENTS:THYRISTOR  
PART NUMBER:2N6508  
MANUFACTURER: ON SEMICONDUCTOR



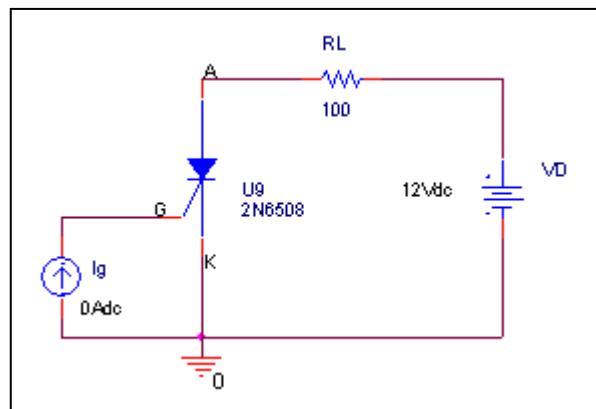
**Bee Technologies Inc.**

## DIODE MODEL

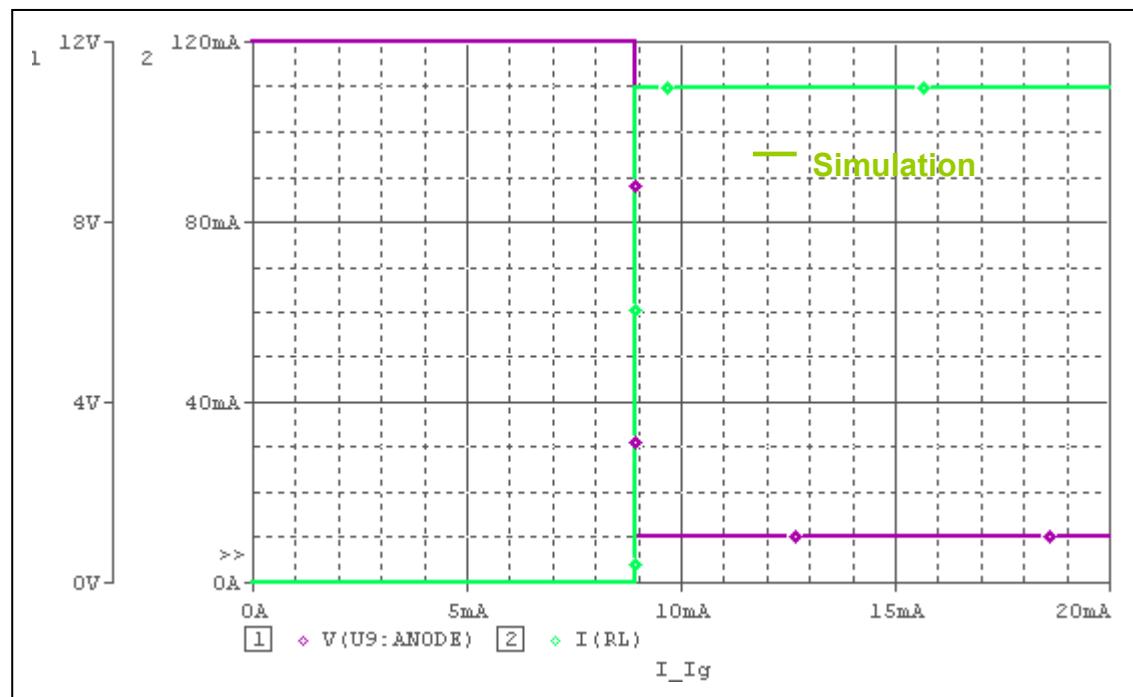
Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

## IG-VT Characteristic

Evaluation Circuit



Simulation result

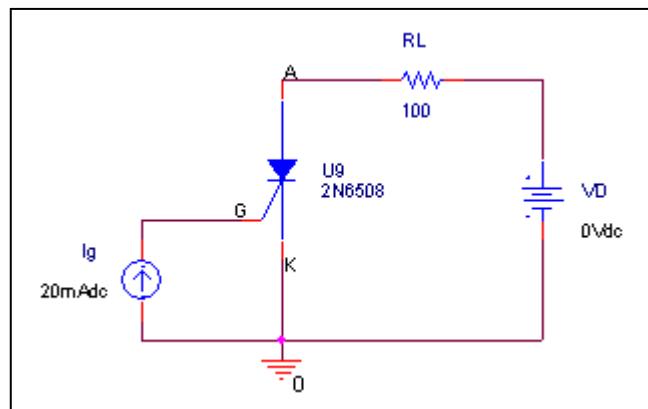


Comparison Table

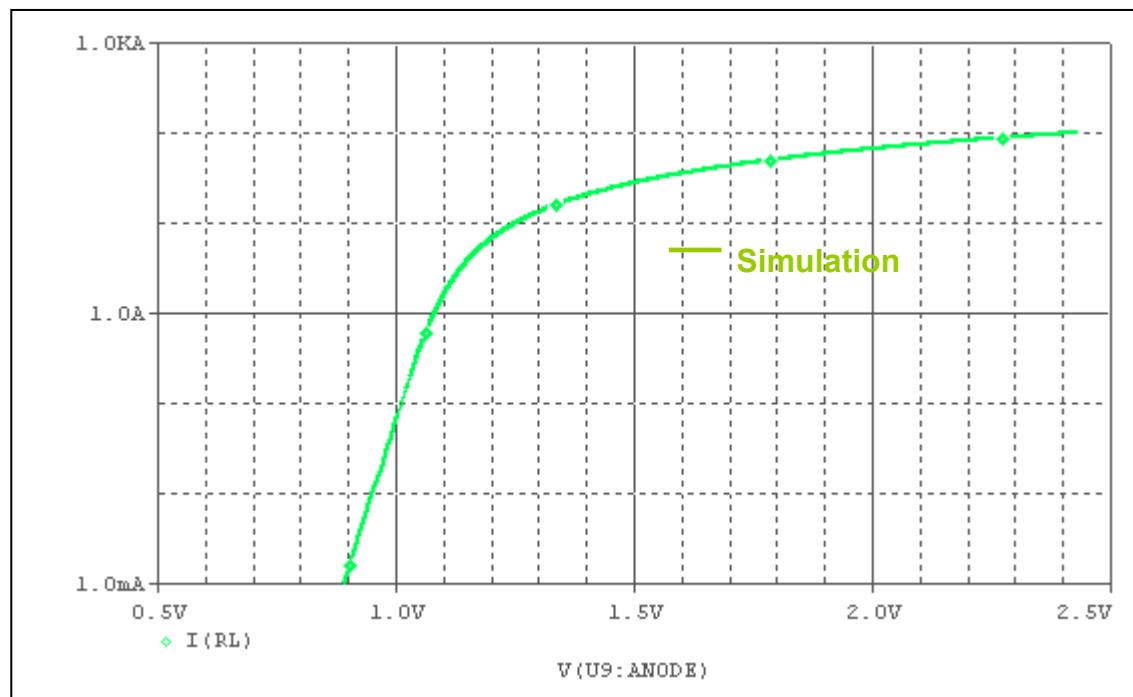
	Measurement	Simulation	% Error
$I_{G_T}$ (mA)	9	8.9300	-0.77778
$V_{G_T}$ (V)	1.0	1.0135	1.35000

## ITM-VTM Characteristic

Evaluation Circuit



Simulation result

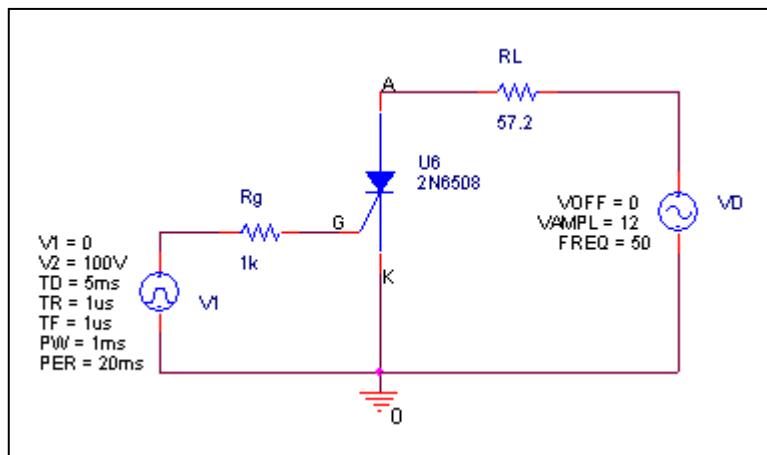


Comparison Table

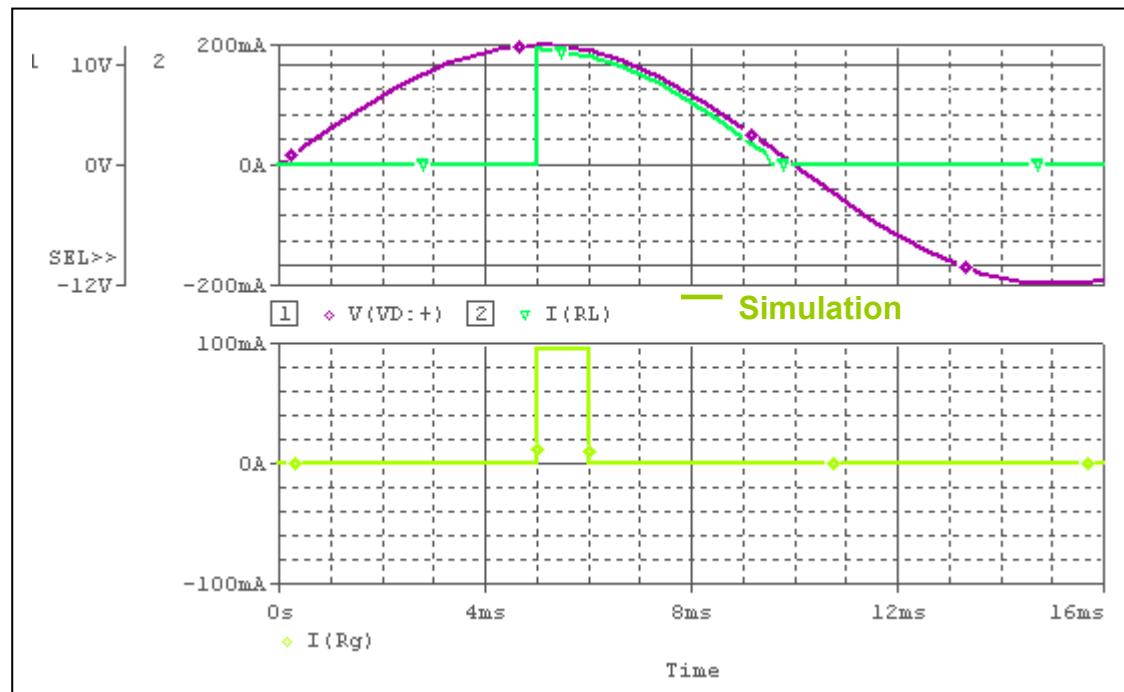
At ITM=50	Measurement	Simulation	% Error
VTM(V)	1.8(max)	1.7919	-0.45000

## Holding Characteristic (IH)

Evaluation Circuit



Simulation result

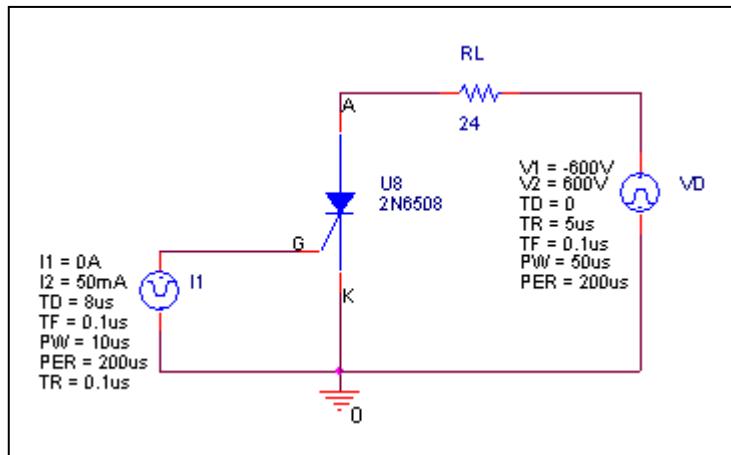


Comparison Table

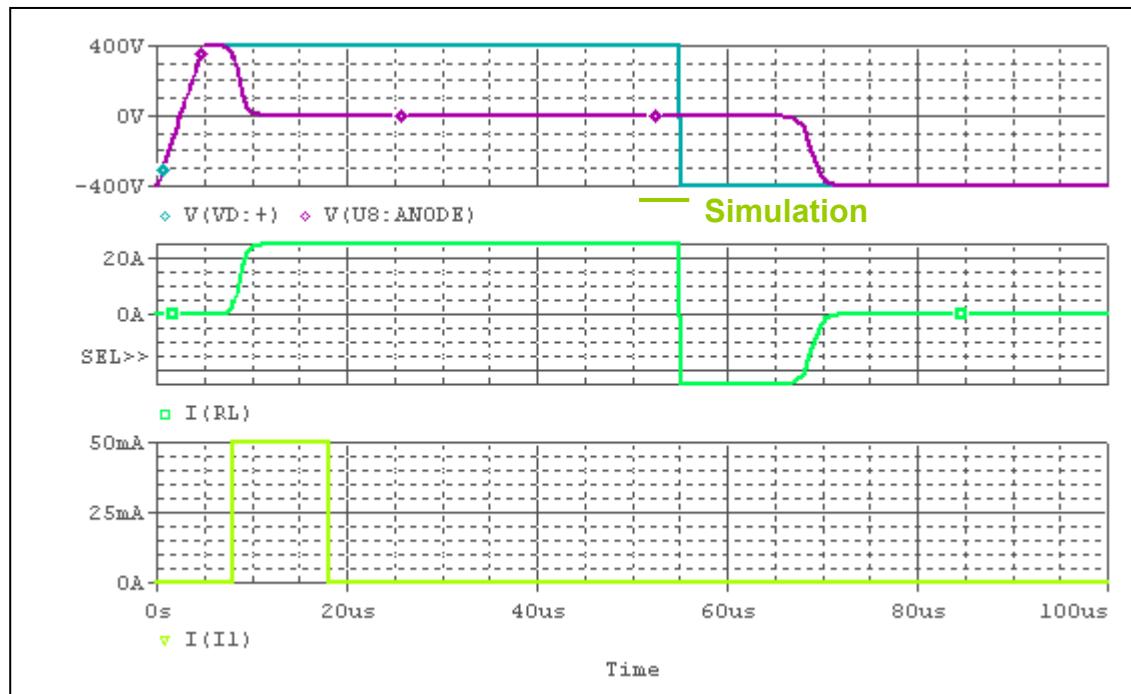
VD=12V	Measurement	Simulation	% Error
IH(mA)	18	17.503	-2.76111

## Switching Time Characteristic

Evaluation Circuit



Simulation result



Comparison Table

	Measurement	Simulation	%Error
Ton(us)	1.5	1.4983	-0.11333
Toff(us)	15	15.014	0.09333